科技大學低成就學生於全民英檢初級圖片題 聽力測驗之表現探討

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本研究旨在探討科技大學低成就學生在全民英檢初級圖片題聽力測驗之表現。參與者為一百五十位南台灣某所科技大學非英語系一年級學生,試題來源為財團法人語言訓練測驗中心官方版聽力練習測驗。學生在測後訪談中,於相同之受測條件根據原始答案逐題回應答題策略及選擇錯誤選項之原因。綜合成績分析及學生訪談結果,本研究發現學生的整體表現突顯其聽力微觀技巧能力之不足。同時,在妨礙學生英語聽力之主要因素中,除「圖片詮釋」為非語言因素外,其他皆隸屬語言因素。面對目前聽力策略潮流傾向過度著力宏觀技巧之景況,本文就分析結果建議正視科技大學一年級學生微觀技巧之學習需求,並盼藉此聽力障礙因素之解析提供未來聽力策略設計與發展之參考。

關鍵詞:圖片題聽力測驗,聽力表現,由下而上模式,微觀技巧

The Performance of the Less Proficient Technological University Students in the Elementary Level GEPT Picture Description Listening Comprehension Test

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Abstract

This study investigates the less proficient technological university students' performance in the GEPT picture description listening comprehension test. A total of 150 non-English-major freshmen from a technological university in southern Taiwan participated in the study. test was sourced from the elementary level GEPT practice tests by the Language Training & Testing Center. In the post-test oral interviews, the participants, examining every single question, were guided to recollect their test-taking strategies and the reasons for selecting the incorrect answers on the foundation of their written responses in the answer sheets. Based on the analysis of the test results and the interviews, the participants' overall performance listening microskills was diagnosed as Additionally, all the factors that hindered the participants' listening proficiency were linguistic factors except for the non-linguistic one - Picture Interpretation. Confronting the current trend of EFL listening strategies that has tended to overemphasize macroskill techniques, the study prompts the attention to the microskill training needs of the less proficient technological Furthermore, the main factors emerged from the university students. participants' listening difficulties are contributed in the hope of being a reference of the future strategy design and development.

Keywords: picture description listening comprehension test, listening performance, bottom-up model, microskill